2SB0790 (2SB790)

Silicon PNP epitaxial planar type

For low-frequency output amplification

■ Features

- Low collector-emitter saturation voltage V_{CE(sat)}
- M type package allowing easy automatic and manual insertion as well as stand-alone fixing to the printed circuit board.

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	-25	V	
Collector-emitter voltage (Base open)	V _{CEO}	-20	V	
Emitter-base voltage (Collector open)	V_{EBO}	-7	V	
Collector current	I_C	- 0.5	A	
Peak collector current	I _{CP}	-1	A	
Collector power dissipation	P _C	600	mW	
Junction temperature	Tj	150	°C	
Storage temperature	T _{stg}	-55 to +150	°C	

Unit: mm 6.9±0.1 (1.5) (1.5) (1.5) (1.6) (1.6) (1.7) (1.6) (1.7) (1.7) (1.8

■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V_{CBO}	$I_{\rm C} = -10 \mu A, I_{\rm E} = 0$	-25			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = -1 \text{ mA}, I_B = 0$	-20			V
Emitter-base voltage (Collector open)	V_{EBO}	$I_E = -10 \mu A, I_C = 0$	-7			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = -25 V_{E} = 0$			- 0.1	μΑ
Collector-emitter cutoff current (Base open)	I _{CEO}	$V_{CE} = -20 \text{ V}, I_{B} = 0$			-1	μΑ
Forward current transfer ratio *1	h _{FE1} * ²	$V_{CE} = 2 \text{ V}, I_{C} = -0.5 \text{ A}$	90		220	_
	Ch _{FE2}	$V_{CE} = -2 \text{ V}, I_{C} = -1 \text{ A}$	25			_
Collector-emitter saturation voltage *	V _{CE(sat)}	$I_C = -500 \text{ mA}, I_B = -50 \text{ mA}$			- 0.4	V
Base-emitter saturation voltage *	V _{BE(sat)}	$I_C = -500 \text{ mA}, I_B = -50 \text{ mA}$			-1.2	V
Transition frequency	f_T	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		15	25	pF
(Common base, input open circuited)						

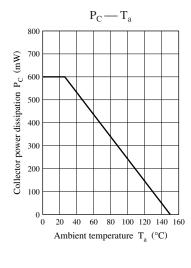
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

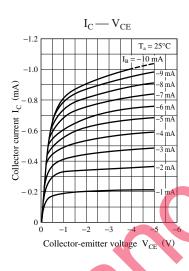
2. *1: Pulse measurement

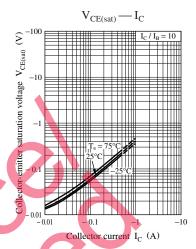
*2: Rank classification

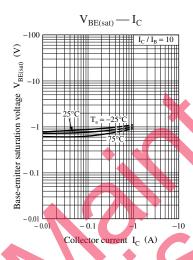
Rank	Q	R		
h _{FE1}	90 to 155	130 to 220		

Note) The part number in the parenthesis shows conventional part number.

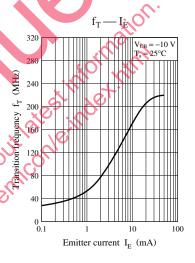


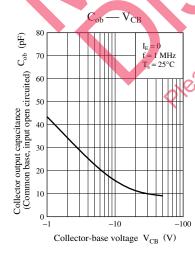












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